IEEE PES Switchgear Committee, HVCB, HVCB Quality & Reliability WG Meeting in Denver, CO

- 1. Welcome and introductions of all participants. The WG meeting was attended by 30 participants; 19 members and 11 guests.
- 2. The WG Chair reviewed IEEE Policy on patents and Other Guidelines for IEEE WG Meetings
- 3. The minutes of the WG meeting in Asheville were approved by the members of the WG.
- 4. The participants divided in groups to work on the different areas.
- 5. Each group leader will compile the comments of their respective group and send them to Bergman and Aristizabal to incorporate into a new draft that would be circulated among all the members.
- 6. The outline of the draft Guide and the list of members are included in the minutes as an additional document.
- 7. All the parts of the document will be collected before the next meeting, a new draft will be circulated among members of the WG to discuss, and a ballot will be held before the next meeting in Myrtle Beach.

See attached outline and task force members.

W.J. (Bill) Bergman <u>bergman@ieee.org</u> Mauricio Aristizabal <u>m.aristizabal@ieee.org</u>

PC37.06D0.5 Proposed Outline

Clause	Title	TF Members
1.	Overview	All
1.1	Scope	
1.2	Purpose	
2.	Normative References	Bill Bergman, Mirko Palazzo
3.	Definitions	all
4.	Procedure for Investigation of Circuit Breaker Failures	Devki Sharma, Joanne Hu, Bruno Bisewski, Brian Berner, Dave Lombardo, Brad Staley, John Webb , Frank Blalock, Doug Giraud, David Mitchell, Kamran Majeed, Eldridge Byron
4.1	Classification of Failures	Alan Storms
5.	Failure Analysis Techniques	Devki Sharma, Rod Sauls , Chih Chow, Arben Bufi, Mike Orosz
6.	Diagnostic Tests and Advanced Diagnostics	Mike Crawford, Paul Barnett, Mauricio Aristizabal , Yasin Musa, Albert Livshitz, Jeff Mizener, Mike Skidmore, Vincent Marshall, Helmut Heiermeier
6.1	Diagnostic Tests	Carlos Isaac, Bill Fernihough
6.2	Advanced Diagnostics	Anne Bosma, Mietek Glinkowski
7.	Data Collection and	Devki Sharma, Hua Liu, Joanne Hu, Bruno Bisewski,
	Data Structure	John Webb, Frank Blalock, Ken Edwards
8.	Failure report utilization	
8.1	Failure Report utilization – General	
8.2	Failure Report utilization – Circuit breaker user	Paul Barnett , Pat DiLillo, Mietek Glinkowski, Dave Galicia, Cory Johnson, Mike Anderson, Don Cantrelle, Cindy Zhang (wouldn't it be good to have a manufacturer to observe or offer information?)
8.3	Failure Report utilization – Circuit breaker manufacturer	Stan Billings, Mauricio Aristizabal, Eldridge Byron , Bill Long, Tony Ricciuti, Pat DiLillo (main observer)
Annex A	Circuit Breaker Design and Construction	Doug Giraud, Eldridge Byron, Mike Orosz, Bjorn Lufgren
A.1	Overview	
A.2	Purpose	
A.3	Types of Circuit Breakers	
A.4	Interruption Mediums of Circuit Breakers	
A.5	Mechanisms of Circuit Breakers	
A.6	Circuit Breaker Operation	
Annex B	Bibliography	Bill Bergman

B.1	Guides to Reliability	
	Design/Analysis	
B.2	Failure Investigation	
B.3	Guides to Failure	
	Reporting	
B.4	Equipment Failure	
	Statistics	
B.5	Guide to Equipment	
	Monitoring	

TF leader highlighted